**III WORKSHOP ON MATERIALS CHARACTERISATION BY DIFFRACTION METHODS**

**January 23th 2017**

**09:00 REGISTRATION**

**09:30 WORKSHOP PRESENTATION AND BRIEF INTRODUCTION**

**Prof. Xavier Obradors (Director of ICMAB)**

**Prof. Jordi Rius (Organizer of the workshop)**

**9:45 Dr. Enrico Mugnanioli (University of Siena)**

*“Application of electron diffraction tomography to nanomaterials characterisation”*

**10:45 Dr. Josep Bassas (CCiTUB, University of Barcelona)**

*“ High resolution X-ray diffraction “*

**11:15 COFFEE BREAK**

**11:45 Dr. Jose Santiso (CIN2)**

*“Application of X-ray diffraction for time-resolved experiments on thin films*

*under non-ambient conditions”*

**12:30 Lcda. Anna Crespi (ICMAB-CSIC)**

*“Applications of 2D detectors to materials characterisation (textures)”*

**13:00 Dr. Carlos Frontera (ICMAB-CSIC)**

*“3D reciprocal space maps in thin films”*

**13:30 LUNCH BREAK**

**15:00 Dr. Xavier Alcobé (CCiTUB, University of Barcelona)**

*“Application of XRD to the quantitative analysis of materials”*

**15:45 Dr. Oriol Vallcorba (ALBA-CELLS)**

*"Synchrotron tts-microdiffraction and related transmission diffraction methodologies for materials characterisation"*

**16:30 END OF WORKSHOP**